

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/516,718	HAJIME ODA, CHIBA-KEN	
		Examiner	Art Unit	Page 1 of 1
		Aditya S Bhat	2863	

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Application/Control No.

09/516,718

Applicant(s)/Patent Under

Reexamination

HAJIME ODA, CHIBA-KEN

Examiner

Aditya S Bhat

Art Unit

2854

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